

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1421	PRIORITY SERIAL NO. 09/497,080	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Sujit Sharan et al.		
					PRIORITY FILING DATE February 2, 2000		PRIORITY GROUP 2825
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	4,839,306	6/1989	Wakamatsu			
	AB	6,030,881	2/2000	Papasouliotis et al			
	AC	5,872,058	2/1999	Van Cleemput +			
	AD	5,614,055	3/1997	Fairbairn et al			
	AE	5,270,264	12/1993	Andideh et al			
	AF	6,015,759	1/2000	Khan et al			
	AG	5,966,616	10/1999	Woerlee			
	AH	5,968,610	10/1999	Liu et al			
	AI	5,679,606	10/1997	Wang et al			
	AJ	6,077,786	5/1997	Chakravarti et al			
	AK	5,731,241	5/1997	Jang et al			
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		Document Number	Date	Country	Class	Subclass	Translation
	AL	WO 97/24761	07/97	PCT			Yes No
	AM	EP 0 843 348	11/97	Europe			
	AN	8-8232 and abstract	01/96	Japan			
	AO						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AP	Gross, M., "Silicon Dioxide Trench Filling Process in a Radio-Frequency Hollow Cathode Reactor", J. Vac. Sci. Technol. B11(2), Mar/Apr. 1993, No. 2, pp. 242-248.					
	AQ	Lee et al, "A low Redeposition Rate High Density plasma CVD process for high aspect ratio 175 nm Tehcnology and beyond, IITC 99, pgs 152-154 0-7803-5174-6/99 IEEE					
	AR	Jung et al "Enhancing uniformity of borderless VIA resistance by HDP oxide technology" ST-P06 0-7803-5727-2/99 Pgs. 452-455					
EXAMINER 		DATE CONSIDERED  2/11/2005					
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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			APPLICANT Sujit Sbaran et al.				
			PRIORITY FILING DATE February 2, 2000		PRIORITY GROUP 2825		
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	6,174,785	6/1998	Parekh et al			
	AB	6,165,854	5/1998	Wu			
	AC	5,447,884	6/1994	Fahey et al			
	AD	5,726,090	5/1997	Jang et al			
	AE	5,660,895	4/1996	Leo et al			
	AF	6,194,038	3/1998	Roszman			
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	AK	5,726,097	3/1998	Yanagida			
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	AL	07-76777	03/1995	Japan			Yes
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		LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			APPLICANT Sujit Sharai et al.			
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*Examiner's Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,114,216	11/1996	Yieh et al				
	AB	6,255,211	10/1999	Olsen et al				
	AC	5,180,490	1/2001	Vassiliev et al				
	AD	6,136,685	10/2000	Narwankar et al				
	AE	6,140,208	10/2000	Agabi et al				
	AF	5,763,315	06/1998	Benedict et al				
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	AQ							
	AR							
	AS							
EXAMINER <i>Hamilton</i>		DATE CONSIDERED <i>2/14/2005</i>						
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